

Notice of References Cited

Application/Control No.

10/782,529

Applicant(s)/Patent Under
Reexamination
CHAUHAN ET AL.

Examiner

David Garcia Cervetti

Art Unit

2136

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,297,239 A	03-1994	Kurosawa et al.	706/59
*	B	US-5,361,353 A	11-1994	Carr et al.	719/313
*	C	US-5,423,041 A	06-1995	Burke et al.	717/117
*	D	US-5,481,717 A	01-1996	Gaboury, Pierre	717/126
*	E	US-5,740,323 A	04-1998	Nomura et al.	706/13
*	F	US-6,014,518 A	01-2000	Steensgaard, Bjarne	717/154
*	G	US-2001/0056444 A1	12-2001	Ide et al.	707/513
*	H	US-2002/0083178 A1	06-2002	Brothers, John David West	709/226
*	I	US-6,427,234 B1	07-2002	Chambers et al.	717/140
*	J	US-2002/0091701 A1	07-2002	Wall et al.	707/100
*	K	US-6,424,958 B1	07-2002	Pappalardo et al.	706/8
*	L	US-2002/0133806 A1	09-2002	Flanagan et al.	717/123
*	M	US-6,484,312 B1	11-2002	Morrison, Vance P.	717/146

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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	U					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,477,529 B1	11-2002	Mousseau et al.	707/5
*	B	US-6,598,186 B1	07-2003	McGuire et al.	714/48
*	C	US-2003/0154296 A1	08-2003	Noguchi et al.	709/229
*	D	US-2003/0229605 A1	12-2003	Herrera et al.	706/47
*	E	US-6,681,385 B1	01-2004	Steensgaard et al.	717/133
*	F	US-2004/0015463 A1	01-2004	Herrera et al.	706/47
*	G	US-2004/0148592 A1	07-2004	Vion-Dury, Jean-Yves	717/152
*	H	US-6,772,410 B1	08-2004	Komatsu et al.	717/124
*	I	US-2004/0268234 A1	12-2004	Sampathkumar et al.	715/513
*	J	US-2005/0027799 A1	02-2005	Tsutsui et al.	709/204
*	K	US-6,917,972 B1	07-2005	Basko et al.	709/224
*	L	US-6,996,813 B1	02-2006	Sokolov et al.	717/148
*	M	US-7,089,542 B2	08-2006	Brand et al.	717/143

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0200449 A1	09-2006	Pauws, Steffen Clarence	707/003
*	B	US-7,120,902 B2	10-2006	Flanagan et al.	717/130
*	C	US-7,191,163 B2	03-2007	Herrera et al.	706/47
*	D	US-7,284,242 B2	10-2007	Vion-Dury, Jean-Yves	717/159
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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